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TITLE: Tester for integrated circuits

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Brief Summary Text - BSTX (4):

Before an integrated circuit is placed in a final product, electrical testing must be performed to insure that the integrated circuit is not defective. With the increase in complexity of integrated circuits, the time required to perform the necessary testing has increased exponentially. The complexities of the testing process have become so great that testing has become a bottleneck in the manufacturing process. This is particularly true with custom integrated circuits such as programmable arrays and application specific integrated circuits (ASICs). For these custom circuits, specific, carefully designed testing programs must be performed to insure that the customized integrated circuit meets the customer's specifications.